

DS08MB200 Dual 800 Mbps 2:1/1:2 LVDS Mux/Buffer

General Description

The DS08MB200 is a dual-port 1 to 2 repeater/buffer and 2 to 1 multiplexer. High-speed data paths and flow-through pinout minimize internal device jitter and simplify board layout. The differential inputs and outputs interface to LVDS or Bus LVDS signals such as those on National's 10-, 16-, and 18- bit Bus LVDS SerDes, or to CML or LVPECL signals.

The 3.3V supply, CMOS process, and robust I/O ensure high performance at low power over the entire industrial -40 to $+85^{\circ}$ C temperature range.

Features

- Up to 800 Mbps data rate per channel
- LVDS/BLVDS/CML/LVPECL compatible inputs, LVDS compatible outputs
- Low output skew and jitter
- On-chip 100Ω input termination
- 15 kV ESD protection on LVDS Inputs/Outputs
- Hot plug Protection
- Single 3.3V supply
- Industrial -40 to +85°C temperature range
- 48-pin LLP Package



Pin Descriptions

Pin	LLP Pin		Description			
Name	Number	i/O, Type	Description			
SWITCH SI	DE DIFFERI	ENTIAL INP	UTS			
SIA_0+	30	I, LVDS	Switch A-side Channel 0 inverting and non-inverting differential inputs. LVDS, Bus LVDS, CML,			
SIA_0-	29		or LVPECL compatible.			
SIA_1+	19	I, LVDS	Switch A-side Channel 1 inverting and non-inverting differential inputs. LVDS, Bus LVDS, CML,			
SIA_1-	20		or LVPECL compatible.			
SIB_0+	28	I, LVDS	Switch B-side Channel 0 inverting and non-inverting differential inputs. LVDS, Bus LVDS, CML,			
SIB_0-	27		or LVPECL compatible.			
SIB_1+	21	I, LVDS	Switch B-side Channel 1 inverting and non-inverting differential inputs. LVDS, Bus LVDS, CML,			
SIB_1-	22		or LVPECL compatible.			
LINE SIDE	DIFFERENT	IAL INPUTS				
LI_0+	40	I, LVDS	Line-side Channel 0 inverting and non-inverting differential inputs. LVDS, Bus LVDS, CML, or			
LI_0-	39		LVPECL compatible.			
LI_1+	9	I, LVDS	Line-side Channel 1 inverting and non-inverting differential inputs. LVDS, Bus LVDS, CML, or			
LI_1-	10		LVPECL compatible.			
SWITCH S	DE DIFFER	ENTIAL OUT	IPUTS			
SOA_0+	34	O, LVDS	Switch A-side Channel 0 inverting and non-inverting differential outputs. LVDS compatible (Notes			
SOA_0-	33		1, 3).			
SOA_1+	15	O, LVDS	Switch A-side Channel 1 inverting and non-inverting differential outputs. LVDS compatible (Notes			
SOA_1-	16		1, 3).			
SOB_0+	32	O, LVDS	Switch B-side Channel 0 inverting and non-inverting differential outputs. LVDS compatible (Notes			
SOB_0-	31		1, 3).			
SOB_1+	17	O, LVDS	Switch B-side Channel 1 inverting and non-inverting differential outputs. LVDS compatible (Notes			
SOB_1-	18		1, 3).			
LINE SIDE	DIFFERENT	IAL OUTPU	TS			
LO_0+	42	O, LVDS	Line-side Channel 0 inverting and non-inverting differential outputs. LVDS compatible (Notes 1,			
LO_0-	41		3).			
LO_1+	7	O, LVDS	Line-side Channel 1 inverting and non-inverting differential outputs. LVDS compatible (Notes 1,			
LO_1-	8		3).			
DIGITAL C	ONTROL IN	TERFACE				
MUX_S0	38	I, LVTTL	Mux Select Control Inputs (per channel) to select which Switch-side input, A or B, is passed			
MUX_S1	11		through to the Line-side.			
ENA_0	36	I, LVTTL	Output Enable Control for Switch A-side and B-side outputs. Each output driver on the A-side and			
ENA_1	13		B-side has a separate enable pin.			
ENB_0	35					
ENB_1	14					
ENL_0	45	I, LVTTL	Output Enable Control for The Line-side outputs. Each output driver on the Line-side has a			
ENL_1	4		separate enable pin.			
POWER						
V _{DD}	6, 12, 37, 43, 48	I, Power	$V_{DD} = 3.3V \pm 0.3V.$			
GND	2, 3, 46, 47	I, Power	Ground reference for LVDS and CMOS circuitry.			
	(Note 2)		For the LLP package, the DAP is used as the primary GND connection to the device. The DAP			
			is the exposed metal contact at the bottom of the LLP-48 package. It should be connected to the			
			ground plane with at least 4 vias for optimal AC and thermal performance.			
N/C	1, 5, 23,		No Connect			
	24, 25, 26,					
	44					
Note 1: For Note 2: Not	interfacing LVE te that the DAP	S outputs to Clong the backside	ML or LVPECL compatible inputs, refer to the applications section of this datasheet. e of the LLP package is the primary GND connection for the device when using the LLP package.			

Note 3: The LVDS outputs do not support a multidrop (BLVDS) environment. The LVDS output characteristics of the DS08MB200 device have been optimized for point-to-point backplane and cable applications.

www.national.com



Ň GND ENL GND Š 11 11 V_{DD} ENA 1 Channel 1 GND ENB 1 SOA 1-1 GND Γ... SOA 1 ENL 0 N/C SOB 1+ Channel 0 SOB 1-VDD LO 04 SIA_1+ LO 0-SIA 1-SIB_1+ LI 0+ LI_0-SIB 1-MUX_SO N/C N/C C V_{DD} SIB_0-SIA_0-SOB_0-SOB_0+ Š NO SIA 0+ SOA_0+ ENA 0 ÷ SOA_0-ENB SIB 20157403 **Directional Signal Paths Top View** (Refer to pin names for signal polarity)

TRI-STATE and Powerdown Modes

The DS08MB200 has output enable control on each of the six onboard LVDS output drivers. This control allows each output individually to be placed in a low power TRI-STATE mode while the device remains active, and is useful to reduce power consumption on unused channels. In TRI-STATE mode, some outputs may remain active while some are in TRI-STATE.

When all six of the output enables (all drivers on both channels) are deasserted (LOW), then the device enters a Powerdown mode that consumes only 0.5mA (typical) of supply current. In this mode, the entire device is essentially powered off, including all receiver inputs, output drivers and internal bandgap reference generators. When returning to active mode from Powerdown mode, there is a delay until valid data is presented at the outputs because of the ramp to power up the internal bandgap reference generators.

Any single output enable that remains active will hold the device in active mode even if the other five outputs are in TRI-STATE.

When in Powerdown mode, any output enable that becomes active will wake up the device back into active mode, even if the other five outputs are in TRI-STATE.

Input Failsafe Biasing

External pull up and pull down resistors may be used to provide enough of an offset to enable an input failsafe under open-circuit conditions. This configuration ties the positive LVDS input pin to VDD thru a pull up resistor and the negative LVDS input pin is tied to GND by a pull down resistor. The pull up and pull down resistors should be in the $5k\Omega$ to $15k\Omega$ range to minimize loading and waveform distortion to the driver. Please refer to application note AN-1194, "Failsafe Biasing of LVDS Interfaces" for more information.

Output Characteristics

The output characteristics of the DS08MB200 have been optimized for point-to-point backplane and cable applications, and are not intended for multipoint or multidrop signaling.

Multiplexer Truth Table (Note 4)

Data I	nputs	Contro	Output		
SIA_0	SIB_0	MUX_S0	ENL_0	LO_0	
Х	valid	0	1	SIB_0	
valid	Х	1	1	SIA_0	
Х	Х	Х	0 (Note 5)	Z	

X = Don't Care

Z = High Impedance (TRI-STATE)

Repeater/Buffer Truth Table (Note 4)

Data Input	Control Inputs		Outputs		
LI_0	ENA_0	ENB_0	SOA_0	SOB_0	
Х	0	0	Z (Note 5)	Z (Note 5)	
valid	0	1	Z	LI_0	
valid	1	0	LI_0	Z	
valid	1	1	LI_0	LI_0	

X = Don't Care

Z = High Impedance (TRI-STATE)

Note 4: Same functionality for channel 1

Note 5: When all enable inputs from both channels are Low, the device enters a powerdown mode. Refer to the applications section titled TRI-STATE and Powerdown modes.

Absolute Maximum Ratings (Note 6)

	-
Supply Voltage (V _{DD})	-0.3V to +4.0V
CMOS Input Voltage	-0.3V to (V _{DD} +0.3V)
LVDS Receiver Input Voltage (Note	
7)	-0.3V to (V _{DD} +0.3V)
LVDS Driver Output Voltage	-0.3V to (V _{DD} +0.3V)
LVDS Output Short Circuit Current	+40 mA
Junction Temperature	+150°C
Storage Temperature	–65°C to +150°C
Lead Temperature (Solder, 4sec)	260°C
Max Pkg Power Capacity @ 25°C	5.2W
Thermal Resistance (θ_{JA})	24°C/W
Package Derating above +25°C	41.7mW/°C
ESD Last Passing Voltage	
HBM, 1.5kΩ, 100pF	8kV
LVDS pins to GND only	15kV

EIAJ, 0Ω, 200pF	250\
CDM	1000\

Recommended Operating Conditions

Supply Voltage (V _{CC})	3.0V to 3.6V
Input Voltage (V _I) (Note 7)	0V to V _{CC}
Output Voltage (V _O)	0V to V _{CC}
Operating Temperature (T _A)	
Industrial	–40°C to +85°C

Note 6: Absolute maximum ratings are those values beyond which damage to the device may occur. The databook specifications should be met, without exception, to ensure that the system design is reliable over its power supply, temperature, and output/input loading variables. National does not recommend operation of products outside of recommended operation conditions.

Note 7: V_{ID} max < 2.4V

Electrical Characteristics

Over recommended operating supply and temperature ranges unless other specified.

Symbol	Parameter	Conditions	Min	Typ (Note 8)	Max	Units	
LVTTL DC SPECIFICATIONS (MUX_Sn, ENA_n, ENB_n, ENL_n)							
V _{IH}	High Level Input Voltage		2.0		V_{DD}	V	
V _{IL}	Low Level Input Voltage		GND		0.8	V	
I _{IH}	High Level Input Current	$V_{IN} = V_{DD} = V_{DDMAX}$	-10		+10	μA	
I	Low Level Input Current	$V_{IN} = V_{SS}, V_{DD} = V_{DDMAX}$	-10		+10	μA	
C _{IN1}	Input Capacitance	Any Digital Input Pin to V_{SS}		3.5		pF	
C _{OUT1}	Output Capacitance	Any Digital Output Pin to V_{SS}		5.5		pF	
V _{CL}	Input Clamp Voltage	I _{CL} = -18 mA	-1.5	-0.8		V	
LVDS INF	PUT DC SPECIFICATIONS (SIA±, SI	B±, Ll±)				-	
V_{TH}	Differential Input High Threshold (Note 9)	V _{CM} = 0.8V or 1.2V or 3.55V, V _{DD} = 3.6V		0	100	mV	
V _{TL}	Differential Input Low Threshold (Note 9)	V _{CM} = 0.8V or 1.2V or 3.55V, V _{DD} = 3.6V	-100	0		mV	
V _{ID}	Differential Input Voltage	$V_{CM} = 0.8V$ to 3.55V, $V_{DD} = 3.6V$	100		2400	mV	
V _{CMR}	Common Mode Voltage Range	V _{ID} = 150 mV, V _{DD} = 3.6V	0.05		3.55	V	
C _{IN2}	Input Capacitance	IN+ or IN– to V _{SS}		3.5		pF	
I _{IN}	Input Current	$V_{IN} = 3.6V, V_{DD} = V_{DDMAX}$	-15		+15	μA	
		$V_{IN} = 0V, V_{DD} = V_{DDMAX}$	-15		+15	μA	
LVDS OUTPUT DC SPECIFICATIONS (SOA_n±, SOB_n±, LO_n±)							
V _{OD}	Differential Output Voltage, (Note 9)	R_L is the internal 100 Ω between OUT+ and OUT–	250	360	500	mV	
ΔV_{OD}	Change in V _{OD} between Complementary States		-35		35	mV	
V _{OS}	Offset Voltage (Note 10)		1.05	1.22	1.475	V	
ΔV_{OS}	Change in V _{OS} between Complementary States		-35		35	mV	
I _{os}	Output Short Circuit Current	OUT+ or OUT- Short to GND		-21	-40	mA	
C _{OUT2}	Output Capacitance	OUT+ or OUT– to GND when TRI- STATE		5.5		pF	

www.national.com

4

Symbol	Parameter	Conditions	Min	Typ (Note 8)	Max	Units
SUPPLY CURRENT (Static)						
I _{CC}	Supply Current	All inputs and outputs enabled and active, terminated with differential load of 100Ω between OUT+ and OUT		225	275	mA
I _{CCZ}	Supply Current - Powerdown Mode	ENA_0 = ENB_0 = ENL_0= ENA_1 = ENB_1 = ENL_1 = L		0.6	4.0	mA
SWITCHI	NG CHARACTERISTICS-LVDS OL	ITPUTS				
t _{LHT}	Differential Low to High Transition Time	Use an alternating 1 and 0 pattern at 200 Mb/s, measure between 20% and 80% of		170	250	ps
t _{HLT}	Differential High to Low Transition Time	V _{OD} . (Note 15)		170	250	ps
t _{PLHD}	Differential Low to High Propagation Delay	Use an alternating 1 and 0 pattern at 200 Mb/s, measure at 50% V _{OD} between		1.0	2.5	ns
t _{PHLD}	Differential High to Low Propagation Delay	input to output.		1.0	2.5	ns
t _{SKD1}	Pulse Skew	It _{PLHD} -t _{PHLD} I (Note 15)		25	75	ps
t _{skcc}	Output Channel to Channel Skew	Difference in propagation delay (t_{PLHD} or t_{PHLD}) among all output channels. (Note 15)		50	115	ps
t _{JIT}	Jitter (Note 11)	RJ - Alternating 1 and 0 at 400 MHz (Note 12)		1.3	1.5	psrms
		DJ - K28.5 Pattern, 800 Mbps (Note 13)		15	34	psp-p
		TJ - PRBS 2 ⁷ -1 Pattern, 800 Mbps (Note 14)		16	34	psp-p
t _{ON}	LVDS Output Enable Time	Time from ENA_n, ENB_n, or ENL_n to OUT± change from TRI-STATE to active.		0.5	1.5	μs
t _{ON2}	LVDS Output Enable time from powerdown mode	Time from ENA_n, ENB_n, or ENL_n to OUT± change from Powerdown to active		10	20	μs
t _{OFF}	LVDS Output Disable Time	Time from ENA_n, ENB_n, or ENL_n to OUT± change from active to TRI-STATE or powerdown.			12	ns

Note 8: Typical parameters are measured at $V_{DD} = 3.3V$, $T_A = 25^{\circ}C$. They are for reference purposes, and are not production-tested.

Note 9: Differential output voltage V_{OD} is defined as ABS(OUT+-OUT-). Differential input voltage V_{ID} is defined as ABS(IN+-IN-).

Note 10: Output offset voltage V_{OS} is defined as the average of the LVDS single-ended output voltages at logic high and logic low states.

Note 11: Jitter is not production tested, but guaranteed through characterization on a sample basis.

Note 12: Random Jitter, or RJ, is measured RMS with a histogram including 1500 histogram window hits. The input voltage = V_{ID} = 500mV, 50% duty cycle at 400 MHz, $t_r = t_f = 50$ ps (20% to 80%).

Note 13: Deterministic Jitter, or D₁, is measured to a histogram mean with a sample size of 350 hits. Stimulus and fixture jitter has been subtracted. The input voltage = V_{ID} = 500mV, K28.5 pattern at 800 Mbps, $t_r = t_f = 50$ ps (20% to 80%). The K28.5 pattern is repeating bit streams of (0011111010 1100000101). Note 14: Total Jitter, or T_J, is measured peak to peak with a histogram including 3500 window hits. Stimulus and fixture jitter has been subtracted. The input voltage = V_{ID} = 500mV, 2⁷⁻¹ PRBS pattern at 800 Mbps, $t_r = t_f = 50$ ps (20% to 80%).

Note 15: Not production tested. Guaranteed by statistical analysis on a sample basis at the time of characterization.

DS08MB200

Typical Performance Characteristics

DS08MB200



Dynamic power supply current was measured with all channels active and tog-one channel active, all other channels are disabled. $V_{DD} = 3.3V$, $V_{ID} = 0.5V$, $V_{CM} = 1.2V$, 800 Mbps data rate. Stimulus and fixture jitter has been subtracted.



Total Jitter measured at 0V differential while running a PRBS 2⁷⁻¹ pattern with one channel active, all other channels are disabled. $V_{DD} = 3.3V$, $T_A = +25^{\circ}C$, $V_{ID} = 0.5V$. Stimulus and fixture jitter has been subtracted.

www.national.com

Interfacing LVPECL to LVDS

An LVPECL driver consists of a differential pair with coupled emitters connected to GND via a current source. This drives a pair of emitter-followers that require a 50 ohm to $V_{\rm CC}$ -2.0 load. A modern LVPECL driver will typically include the termination scheme within the device for the emitter follower. If the driver does not include the load, then an external scheme must be used. The 1.3 V supply is usually not readily available on a PCB, therefore, a load scheme without a unique power supply requirement may be used.



FIGURE 2. DC Coupled LVPECL to LVDS Interface

Figure 2 is a separated π termination scheme for a 3.3 V LVPECL driver. R1 and R2 provides proper DC load for the driver emitter followers, and may be included as part of the driver device (Note 16). The DS08MB200 includes a 100 ohm input termination for the transmission line. The common mode voltage will be at the normal LVPECL levels – around 2 V. This scheme works well with LVDS receivers that have rail-to-rail common mode voltage, $V_{\rm CM}$, range. Most National Semiconductor LVDS receivers have wide $V_{\rm CM}$ range. The exceptions are noted in devices' respective datasheets. Those LVDS devices that do have a wide $V_{\rm CM}$ range do not vary in performance significantly when receiving a signal with a common mode other than standard LVDS $V_{\rm CM}$ of 1.2 V.



FIGURE 3. AC Coupled LVPECL to LVDS Interface

An AC coupled interface is preferred when transmitter and receiver ground references differ more than 1 V. This is a likely scenario when transmitter and receiver devices are on separate PCBs. *Figure 3* illustrates an AC coupled interface between a LVPECL driver and LVDS receiver. R1 and R2, if not present in the driver device (Note 16), provide DC load for the emitter followers and may range between 140-220 ohms for most LVPECL devices for this particular configuration. The DS08MB200 includes an internal 100 ohm resistor to terminate the transmission line for minimal reflections. The signal after ac coupling capacitors will swing around a level set by internal biasing resistors (i.e. fail-safe) which is either V_{DD}/2 or 0 V depending on the actual failsafe implementation. If internal biasing is not implemented, the signal common mode voltage will slowly wander to GND level.

Interfacing LVDS to LVPECL

An LVDS driver consists of a current source (nominal 3.5mA) which drives a CMOS differential pair. It needs a differential resistive load in the range of 70 to 130 ohms to generate LVDS levels. In a system, the load should be selected to match transmission line characteristic differential impedance so that the line is properly terminated. The termination resistor should be placed as close to the receiver inputs as possible. When interfacing an LVDS driver with a non-LVDS receiver, one only needs to bias the LVDS signal so that it is within the common mode range of the receiver. This may be done by using separate biasing voltage which demands another power supply. Some receivers have required biasing voltage available on-chip (V_T , V_{TT} or V_{BR}).



FIGURE 4. DC Coupled LVDS to LVPECL Interface

Figure 4 illustrates interface between an LVDS driver and a LVPECL with a V_T pin available. R1 and R2, if not present in the receiver (Note 16), provide proper resistive load for the driver and termination for the transmission line, and V_T sets desired bias for the receiver.



FIGURE 5. AC Coupled LVDS to LVPECL Interface

Figure 5 illustrates AC coupled interface between an LVDS driver and LVPECL receiver without a V_T pin available. The resistors R1, R2, R3, and R4, if not present in the receiver (Note 16), provide a load for the driver, terminate the transmission line, and bias the signal for the receiver.

Note 16: The bias networks shown above for LVPECL drivers and receivers may or may not be present within the driver device. The LVPECL driver and receiver specification must be reviewed closely to ensure compatibility between the driver and receiver terminations and common mode operating ranges.



www.national.com

Notes

Notes

For more National Semiconductor product information and proven design tools, visit the following Web sites at:						
Pr	oducts	Design Support				
Amplifiers	www.national.com/amplifiers	WEBENCH	www.national.com/webench			
Audio	www.national.com/audio	Analog University	www.national.com/AU			
Clock Conditioners	www.national.com/timing	App Notes	www.national.com/appnotes			
Data Converters	www.national.com/adc	Distributors	www.national.com/contacts			
Displays	www.national.com/displays	Green Compliance	www.national.com/quality/green			
Ethernet	www.national.com/ethernet	Packaging	www.national.com/packaging			
Interface	www.national.com/interface	Quality and Reliability	www.national.com/quality			
LVDS	www.national.com/lvds	Reference Designs	www.national.com/refdesigns			
Power Management	www.national.com/power	Feedback	www.national.com/feedback			
Switching Regulators	www.national.com/switchers					
LDOs	www.national.com/ldo					
LED Lighting	www.national.com/led					
PowerWise	www.national.com/powerwise					
Serial Digital Interface (SDI)	www.national.com/sdi					
Temperature Sensors	www.national.com/tempsensors					
Wireless (PLL/VCO)	www.national.com/wireless					

THE CONTENTS OF THIS DOCUMENT ARE PROVIDED IN CONNECTION WITH NATIONAL SEMICONDUCTOR CORPORATION ("NATIONAL") PRODUCTS. NATIONAL MAKES NO REPRESENTATIONS OR WARRANTIES WITH RESPECT TO THE ACCURACY OR COMPLETENESS OF THE CONTENTS OF THIS PUBLICATION AND RESERVES THE RIGHT TO MAKE CHANGES TO SPECIFICATIONS AND PRODUCT DESCRIPTIONS AT ANY TIME WITHOUT NOTICE. NO LICENSE, WHETHER EXPRESS, IMPLIED, ARISING BY ESTOPPEL OR OTHERWISE, TO ANY INTELLECTUAL PROPERTY RIGHTS IS GRANTED BY THIS DOCUMENT.

TESTING AND OTHER QUALITY CONTROLS ARE USED TO THE EXTENT NATIONAL DEEMS NECESSARY TO SUPPORT NATIONAL'S PRODUCT WARRANTY. EXCEPT WHERE MANDATED BY GOVERNMENT REQUIREMENTS, TESTING OF ALL PARAMETERS OF EACH PRODUCT IS NOT NECESSARILY PERFORMED. NATIONAL ASSUMES NO LIABILITY FOR APPLICATIONS ASSISTANCE OR BUYER PRODUCT DESIGN. BUYERS ARE RESPONSIBLE FOR THEIR PRODUCTS AND APPLICATIONS USING NATIONAL COMPONENTS. PRIOR TO USING OR DISTRIBUTING ANY PRODUCTS THAT INCLUDE NATIONAL COMPONENTS, BUYERS SHOULD PROVIDE ADEQUATE DESIGN, TESTING AND OPERATING SAFEGUARDS.

EXCEPT AS PROVIDED IN NATIONAL'S TERMS AND CONDITIONS OF SALE FOR SUCH PRODUCTS, NATIONAL ASSUMES NO LIABILITY WHATSOEVER, AND NATIONAL DISCLAIMS ANY EXPRESS OR IMPLIED WARRANTY RELATING TO THE SALE AND/OR USE OF NATIONAL PRODUCTS INCLUDING LIABILITY OR WARRANTIES RELATING TO FITNESS FOR A PARTICULAR PURPOSE, MERCHANTABILITY, OR INFRINGEMENT OF ANY PATENT, COPYRIGHT OR OTHER INTELLECTUAL PROPERTY RIGHT.

LIFE SUPPORT POLICY

NATIONAL'S PRODUCTS ARE NOT AUTHORIZED FOR USE AS CRITICAL COMPONENTS IN LIFE SUPPORT DEVICES OR SYSTEMS WITHOUT THE EXPRESS PRIOR WRITTEN APPROVAL OF THE CHIEF EXECUTIVE OFFICER AND GENERAL COUNSEL OF NATIONAL SEMICONDUCTOR CORPORATION. As used herein:

Life support devices or systems are devices which (a) are intended for surgical implant into the body, or (b) support or sustain life and whose failure to perform when properly used in accordance with instructions for use provided in the labeling can be reasonably expected to result in a significant injury to the user. A critical component is any component in a life support device or system whose failure to perform can be reasonably expected to cause the failure of the life support device or system or to affect its safety or effectiveness.

National Semiconductor and the National Semiconductor logo are registered trademarks of National Semiconductor Corporation. All other brand or product names may be trademarks or registered trademarks of their respective holders.

Copyright© 2007 National Semiconductor Corporation

For the most current product information visit us at www.national.com



National Semiconductor Americas Customer Support Center Email: new.feedback@nsc.com Tel: 1-800-272-9959

 National Semiconductor Europe Customer Support Center

 Fax: +49 (0) 180-530-85-86

 Email: europe.support@nsc.com

 Deutsch Tel: +49 (0) 69 9508 6208

 English Tel: +49 (0) 870 24 0 2171

 Français Tel: +33 (0) 1 41 91 8790
 National Semiconductor Asia Pacific Customer Support Center Email: ap.support@nsc.com National Semiconductor Japan Customer Support Center Fax: 81-3-5639-7507 Email: jpn.feedback@nsc.com Tel: 81-3-5639-7560